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FDMC86160ET100 N-Channel Shielded Gate PowerTrench[®] MOSFET 100 V, 43 A, 14 m Ω

Features

- Extended T_J rating to 175°C
- Shielded Gate MOSFET Technology
- Max $r_{DS(on)} = 14 \text{ m}\Omega$ at $V_{GS} = 10 \text{ V}$, $I_D = 9 \text{ A}$
- Max $r_{DS(on)}$ = 23 m Ω at V_{GS} = 6 V, I_D = 7 A
- High performance technology for extremely low r_{DS(on)}
- Termination is Lead-free and RoHS Compliant

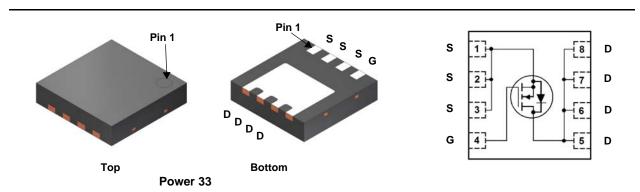


General Description

This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench[®] process that incorporates Shielded Gate technology. This process has been optimized for the on-state resistance. This device is well suited for applications where ulta low $R_{DS\ (on)}$ is required in small spaces such as High performance VRM, POL and orring functions.

Applications

- Bridge Topologies
- Synchronous Rectifier



MOSFET Maximum Ratings T_A = 25 °C unless otherwise noted

Symbol	Parameter				Ratings	Units	
V _{DS}	Drain to Source	/oltage			100	V	
V _{GS}	Gate to Source V	/oltage			±20	V	
ID	Drain Current	-Continuous	T _C = 25 °C	(Note 5)	43		
		-Continuous	T _C = 100 °C	(Note 5)	31	٨	
		-Continuous	T _A = 25 °C	(Note 1a)	9	Α	
		-Pulsed		(Note 4)	204		
E _{AS}	Single Pulse Ava	lanche Energy		(Note 3)	181	mJ	
P _D	Power Dissipation		T _C = 25 °C	T _C = 25 °C		14/	
	Power Dissipation		T _A = 25 °C	(Note 1a)	2.8		
T _J , T _{STG}	Operating and Storage Junction Temperature Range				-55 to +175	°C	

Thermal Characteristics

$R_{ ext{ heta}JC}$	Thermal Resistance, Junction to Case	(Note 1)	2.3	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	53	0/11

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMC86160ET	FDMC86160ET100	Power33	13 "	12 mm	3000 units

Parameter	Test Conditions	Min	Тур	Max	Units
acteristics					
	$I_{D} = 250 \mu A$, $V_{CC} = 0 V$	100			V
-		100			
Coefficient	$I_D = 250 \ \mu$ A, referenced to 25 °C		73		mV/°C
Zero Gate Voltage Drain Current	V _{DS} = 80 V, V _{GS} = 0 V			1	μA
Gate to Source Leakage Current	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$			±100	nA
acteristics					
Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \ \mu A$	2	2.9	4	V
Gate to Source Threshold Voltage Temperature Coefficient	$I_D = 250 \ \mu\text{A}$, referenced to 25 °C		-9		mV/°C
	V _{GS} = 10 V, I _D = 9 A		11.2	14	
Static Drain to Source On Resistance	V _{GS} = 6 V, I _D = 7 A		16	23	mΩ
	V_{GS} = 10 V, I_{D} = 9 A, T_{J} = 125 °C		21	26	
Forward Transconductance	V _{DD} = 10 V, I _D = 9 A		43		S
Characteristics					
			968	1290	pF
	$V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V},$		241	320	pF
	f = 1 MHz				pF
		0.1			ρ. Ω
Characteristics				1	
Turn-On Delay Time			9.7	19	ns
			-		
Rise Time	$V_{PP} = 50 V I_{P} = 9 A$		3.6	10	ns
Rise Time Turn-Off Delay Time	$V_{DD} = 50 \text{ V}, \text{ I}_{D} = 9 \text{ A},$ $V_{CS} = 10 \text{ V}, \text{ R}_{CEN} = 6 \Omega$		3.6 16	10 30	ns ns
Turn-Off Delay Time	$V_{DD} = 50 V, I_D = 9 A,$ $V_{GS} = 10 V, R_{GEN} = 6 Ω$		16	30	ns
Turn-Off Delay Time Fall Time	$V_{GS} = 10 \text{ V}, \text{R}_{\text{GEN}} = 6 \Omega$		16 3.4	30 10	ns ns
Turn-Off Delay Time Fall Time Total Gate Charge	$V_{GS} = 10 \text{ V}, \text{ R}_{GEN} = 6 \Omega$ $V_{GS} = 0 \text{ V to } 10 \text{ V}$		16 3.4 15	30 10 22	ns ns nC
Turn-Off Delay Time Fall Time Total Gate Charge Total Gate Charge	$V_{GS} = 10 \text{ V}, \ \bar{R}_{GEN} = 6 \Omega$ $V_{GS} = 0 \text{ V to } 10 \text{ V}$ $V_{GS} = 0 \text{ V to } 6 \text{ V}$ $V_{DD} = 50 \text{ V},$		16 3.4 15 9.8	30 10	ns ns nC nC
Turn-Off Delay Time Fall Time Total Gate Charge Total Gate Charge Total Gate Charge Total Gate Charge	$V_{GS} = 10 \text{ V}, \text{ R}_{GEN} = 6 \Omega$ $V_{GS} = 0 \text{ V to } 10 \text{ V}$		16 3.4 15 9.8 4.4	30 10 22	ns ns nC nC nC
Turn-Off Delay TimeFall TimeTotal Gate ChargeTotal Gate ChargeTotal Gate ChargeGate to Drain "Miller" Charge	$V_{GS} = 10 \text{ V}, \ \bar{R}_{GEN} = 6 \Omega$ $V_{GS} = 0 \text{ V to } 10 \text{ V}$ $V_{GS} = 0 \text{ V to } 6 \text{ V}$ $V_{DD} = 50 \text{ V},$		16 3.4 15 9.8	30 10 22	ns ns nC nC
Turn-Off Delay Time Fall Time Total Gate Charge Total Gate Charge Total Gate Charge Total Gate Charge	$V_{GS} = 10 \text{ V}, $		16 3.4 15 9.8 4.4 3.5	30 10 22 15	ns ns nC nC nC nC
Turn-Off Delay TimeFall TimeTotal Gate ChargeTotal Gate ChargeTotal Gate ChargeGate to Drain "Miller" Charge	$V_{GS} = 10 \text{ V}, $		16 3.4 15 9.8 4.4	30 10 22	ns ns nC nC nC
Turn-Off Delay Time Fall Time Total Gate Charge Total Gate Charge Total Gate Charge Gate to Drain "Miller" Charge urce Diode Characteristics	$V_{GS} = 10 \text{ V}, \ \bar{R}_{GEN} = 6 \Omega$ $V_{GS} = 0 \text{ V to } 10 \text{ V}$ $V_{GS} = 0 \text{ V to } 6 \text{ V}$ $I_D = 50 \text{ V},$ $I_D = 9 \text{ A}$ $V_{GS} = 0 \text{ V}, \ I_S = 9 \text{ A}$ (Note 2)		16 3.4 15 9.8 4.4 3.5 0.79	30 10 22 15 	ns ns nC nC nC nC V
	Zero Gate Voltage Drain Current Gate to Source Leakage Current Cteristics Gate to Source Threshold Voltage Gate to Source Threshold Voltage Temperature Coefficient Static Drain to Source On Resistance Forward Transconductance Characteristics Input Capacitance Output Capacitance Reverse Transfer Capacitance Gate Resistance Characteristics	Breakdown Voltage Temperature CoefficientIp = 250 μ A, referenced to 25 °CZero Gate Voltage Drain Current $V_{DS} = 80 \text{ V}, V_{GS} = 0 \text{ V}$ Gate to Source Leakage Current $V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$ IntersticsGate to Source Threshold Voltage $V_{GS} = V_{DS}, I_D = 250 \mu$ AGate to Source Threshold Voltage $I_D = 250 \mu$ A, referenced to 25 °CGate to Source Threshold Voltage $I_D = 250 \mu$ A, referenced to 25 °CGate to Source Threshold Voltage $I_D = 250 \mu$ A, referenced to 25 °CStatic Drain to Source On Resistance $V_{GS} = 10 \text{ V}, I_D = 9 \text{ A}$ Vogs = 10 V, I_D = 9 A, T_J = 125 °C $V_{DD} = 10 \text{ V}, I_D = 9 \text{ A}$ Characteristics $V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V}, I_D = 9 \text{ A}$ Input Capacitance $V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V}, I_D = 9 \text{ A}$ Gate Resistance $V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V}, I_D = 9 \text{ A}$ Characteristics $V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V}, I_D = 9 \text{ A}$ Gate Resistance $V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V}, I_D = 9 \text{ A}$ Characteristics $V_{DS} = 50 \text{ V}, V_{SS} = 0 \text{ V}, I_S = 10 \text{ MHz}$ Reverse Transfer Capacitance $V_{DS} = 50 \text{ V}, V_{SS} = 0 \text{ V}, I_S = 10 \text{ MHz}$ Gate Resistance $V_{DS} = 50 \text{ V}, V_{SS} = 0 \text{ V}, I_S = 10 \text{ MHz}$	Breakdown Voltage Temperature CoefficientID 250μ A, referenced to $25 \circ$ CZero Gate Voltage Drain Current $V_{DS} = 80 V, V_{GS} = 0 V$ Gate to Source Leakage Current $V_{GS} = \pm 20 V, V_{DS} = 0 V$ cteristicsGate to Source Threshold Voltage Temperature CoefficientJD $= 250 \mu$ A, referenced to $25 \circ$ CStatic Drain to Source On Resistance $V_{GS} = 10 V, I_D = 9 A$ VGS $= 10 V, I_D = 9 A$ Static Drain to Source On Resistance $V_{GS} = 10 V, I_D = 9 A$ Characteristics $V_{DD} = 10 V, I_D = 9 A$ Input Capacitance $V_{DS} = 50 V, V_{GS} = 0 V, I_D = 9 A$ Characteristics $V_{DS} = 50 V, V_{GS} = 0 V, I_D = 9 A$ Input Capacitance $V_{DS} = 50 V, V_{GS} = 0 V, I_D = 9 A$ Gate Resistance 0.1 Output Capacitance 0.1 Gate Resistance 0.1	Breakdown Voltage Temperature CoefficientID $250 \ \mu$ A, referenced to $25 \ ^{\circ}$ C73Zero Gate Voltage Drain Current Gate to Source Leakage Current $V_{DS} = 80 \ V, V_{GS} = 0 \ V$ 73Gate to Source Leakage Current $V_{GS} = \pm 20 \ V, V_{DS} = 0 \ V$ 73cteristicsGate to Source Threshold Voltage Temperature Coefficient $V_{GS} = V_{DS}, \ I_D = 250 \ \mu$ A22.9Gate to Source Threshold Voltage Temperature Coefficient $V_{GS} = V_{DS}, \ I_D = 250 \ \mu$ A, referenced to $25 \ ^{\circ}$ C-9Static Drain to Source On Resistance $V_{GS} = 10 \ V, \ I_D = 9 \ A$ 11.2VGS = 10 \ V, \ I_D = 9 \ A16VGS = 10 \ V, \ I_D = 9 \ A16VGS = 10 \ V, \ I_D = 9 \ A43CharacteristicsInput Capacitance Output Capacitance $V_{DS} = 50 \ V, \ V_{GS} = 0 \ V, \ 241 \ Reverse Transfer Capacitance968Output CapacitanceGate Resistance0.1 0.6Ocharacteristics$	Breakdown Voltage Temperature CoefficientI I D= 250 μ A, referenced to 25 °C73Zero Gate Voltage Drain CurrentV DS= 80 V, V GS= 0 V1Gate to Source Leakage CurrentV GS= ±20 V, V DS= 0 V±100cteristicsGate to Source Threshold Voltage Temperature CoefficientV I D= 250 μ A, referenced to 25 °C-94Gate to Source Threshold Voltage Temperature CoefficientV I D= 250 μ A, referenced to 25 °C-9-9Static Drain to Source On ResistanceV V S S V DD= 10 V, I D= 9 A11.214VGS GS Forward TransconductanceV DD D= 10 V, I D= 9 A1623VDD Output Capacitance Gate ResistanceV DD F= 10 V, I D= 9 A43

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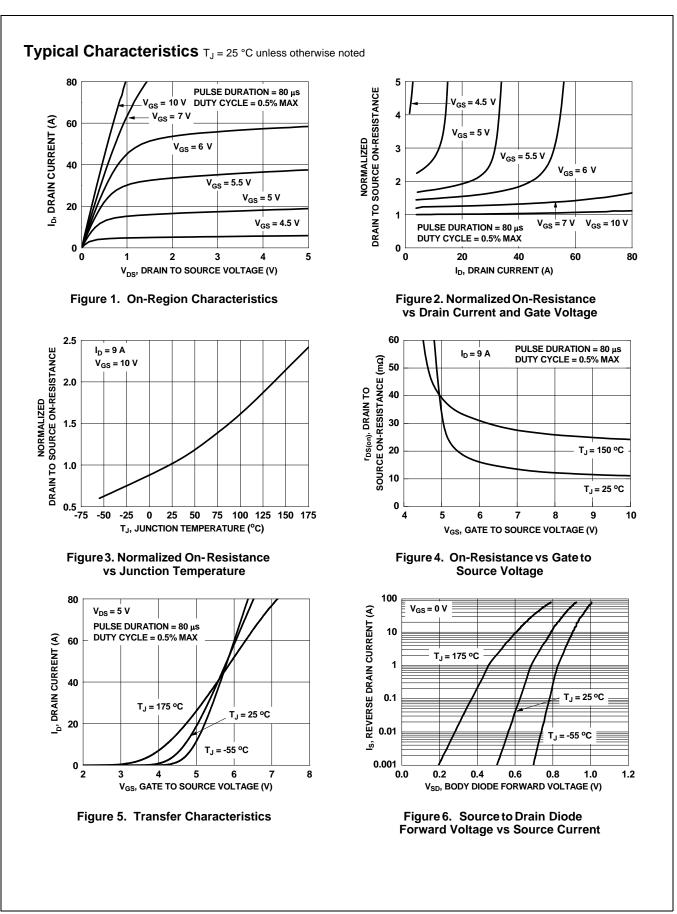
4. Pulsed Id please refer to Fig 11 SOA graph for more details.

5. Computed continuous current limited to Max Junction Temperature only, actual continuous current will be limited by thermal & electro-mechanical application board design.

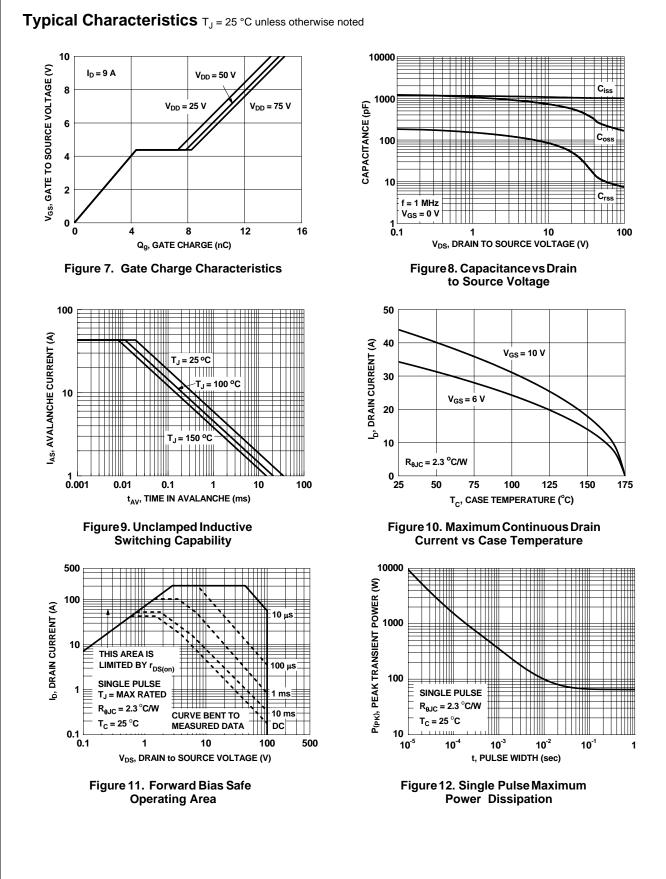
3. E_{AS} of 181 mJ is based on starting T_J = 25 °C, L = 3 mH, I_{AS} = 11 A, V_{DD} = 100 V, V_{GS} = 10 V. 100% test at L = 0.1 mH, I_{AS} = 35 A.

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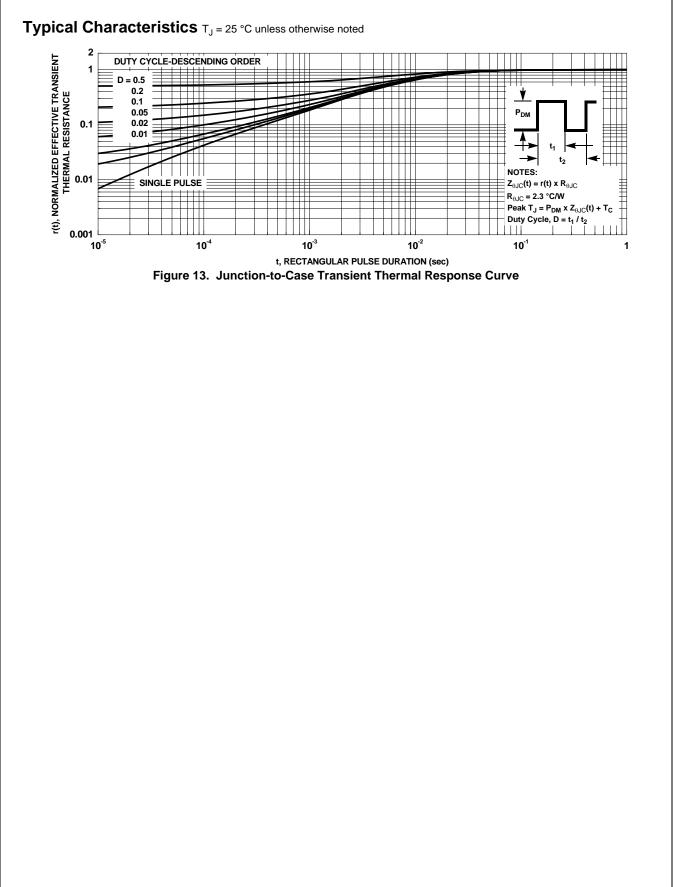
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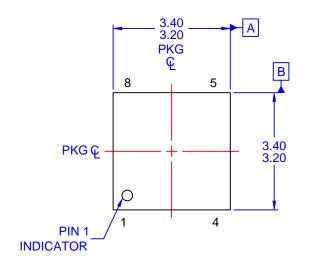


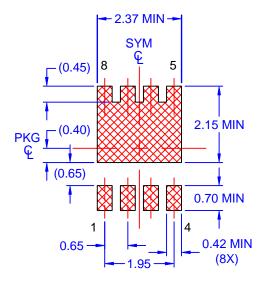
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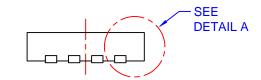
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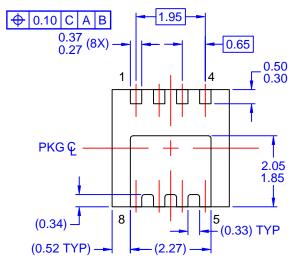


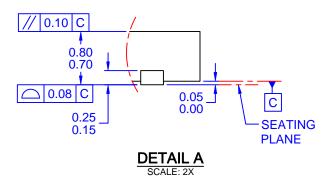












NOTES: UNLESS OTHERWISE SPECIFIED

- A) PACKAGE STANDARD REFERENCE: JEDEC MO-240, ISSUE A, VAR. BA, DATED OCTOBER 2002.
- B) ALL DIMENSIONS ARE IN MILLIMETERS.
- C) DIMENSIONS DO NOT INCLUDE BURRS OR MOLD FLASH. MOLD FLASH OR BURRS DOES NOT EXCEED 0.10MM.
- D) DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.
- E) DRAWING FILE NAME: PQFN08HREV1

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